

INFLUENCE OF THE CURVATURE RADIUS
OF MULTILAYER STRUCTURES ON X-RAY
DIFFRACTION SPECTRA

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S u m m a r y

By the method of high-resolution X-ray diffractometry, we have established the effect of a change of the period of a multilayer periodic structure on a change of its curvature radius. We have explained this phenomenon observed as a variation of the positions of peaks of the satellite structure on the diffraction spectra of X-rays under the influence of a change of the deformation along the growth direction of the structure caused by the diffusion of components in the process of thermoannealing.